



AOS Semiconductor Product Reliability Report

AOUS66616, rev A

Plastic Encapsulated Device

ALPHA & OMEGA Semiconductor, Inc

www.aosmd.com

Dec, 2018

This AOS product reliability report summarizes the qualification result for AOUS66616. Accelerated environmental tests are performed on a specific sample size, and then followed by electrical test at end point. Review of final electrical test result confirms that AOUS66616 passes AOS quality and reliability requirements. The released product will be categorized by the process family and be routine monitored for continuously improving the product quality.

I. Reliability Stress Test Summary and Results

| Test Item | Test Condition | Time Point | Total Sample Size | Number of Failures | Reference Standard |
|--------------------------|--|---------------------------|-------------------|--------------------|--------------------|
| HTGB | Temp = 150°C , Vgs=100% of Vgsmax | 168 / 500 / 1000 hours | 231 pcs | 0 | JESD22-A108 |
| HTRB | Temp = 150°C , Vds=100% of Vdsmax | 168 / 500 / 1000 hours | 231 pcs | 0 | JESD22-A108 |
| Precondition (Note A) | 192hr 30°C / 60%RH + 3 cycle reflow @260°C (MSL 3) | - | 693 pcs | 0 | JESD22-A113 |
| HAST | 130°C , 85%RH, 33.3 psia, Vds = 80% of Vdsmax up to 42V | 96 hours | 231 pcs | 0 | JESD22-A110 |
| Autoclave | 121°C , 29.7psia, RH=100% | 96 hours | 231 pcs | 0 | JESD22-A102 |
| Temperature Cycle | -65°C to 150°C , air to air, | 1000cycles | 231 pcs | 0 | JESD22-A104 |

Note: The reliability data presents total of available generic data up to the published date.

Note A: MSL (Moisture Sensitivity Level) 3 based on J-STD-020

II. Reliability Evaluation

FIT rate (per billion): 7.63

MTTF = 14960 years

The presentation of FIT rate for the individual product reliability is restricted by the actual burn-in sample size. Failure Rate Determination is based on JEDEC Standard JESD 85. FIT means one failure per billion hours.

Failure Rate = $\text{Chi}^2 \times 10^9 / [2 (N) (H) (Af)] = 7.63$

MTTF = $10^9 / \text{FIT} = 14960$ years

Chi² = Chi Squared Distribution, determined by the number of failures and confidence interval

N = Total Number of units from burn-in tests

H = Duration of burn-in testing

Af = Acceleration Factor from Test to Use Conditions (Ea = 0.7eV and Tuse = 55°C)

Acceleration Factor [**Af**] = $\text{Exp} [Ea / k (1/Tj u - 1/Tj s)]$

Acceleration Factor ratio list:

| | 55 deg C | 70 deg C | 85 deg C | 100 deg C | 115 deg C | 130 deg C | 150 deg C |
|-----------|------------|-----------|-----------|-----------|-------------|-------------|-----------|
| Af | 259 | 87 | 32 | 13 | 5.64 | 2.59 | 1 |

Tj s = Stressed junction temperature in degree (Kelvin), K = C+273.16

Tj u = The use junction temperature in degree (Kelvin), K = C+273.16

k = Boltzmann's constant, $8.617164 \times 10^{-5} \text{eV} / \text{K}$